



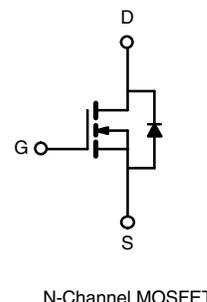
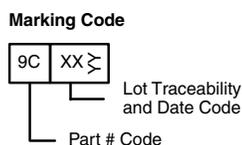
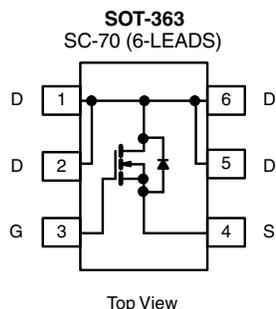
SQ1470EH



PRODUCT SUMMARY	
V _{DS} (V)	30
R _{DS(on)} (Ω) at V _{GS} = 4.5 V	0.065
R _{DS(on)} (Ω) at V _{GS} = 2.5 V	0.095
I _D (A)	2.8
Configuration	Single

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- AEC-Q101 Qualified^d
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2002/95/EC



ORDERING INFORMATION	
Package	SC-70
Lead (Pb)-free and Halogen-free	SQ1470EH-T1-GE3

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	30	V
Gate-Source Voltage		V _{GS}	± 12	
Continuous Drain Current ^a	T _C = 25 °C	I _D	2.8	A
	T _C = 125 °C		2.8	
Continuous Source Current (Diode Conduction) ^a		I _S	2.8	
Pulsed Drain Current ^b		I _{DM}	11	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	10	
Single Pulse Avalanche Energy		E _{AS}	5	
Maximum Power Dissipation ^b	T _C = 25 °C	P _D	3.3	W
	T _C = 125 °C		1.1	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	125	°C/W
Junction-to-Foot (Drain)		R _{thJF}	45	

Notes

- Package limited.
- Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2 %.
- When mounted on 1" square PCB (FR-4 material).
- Parametric verification ongoing.



SQ1470EH

SPECIFICATIONS (T _C = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	30	-	-	V
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	0.6	1.0	1.6	
Gate-Source Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 12 V	-	-	± 500	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 30 V	-	-	1	μA
		V _{GS} = 0 V, V _{DS} = 30 V, T _J = 125 °C	-	-	50	
		V _{GS} = 0 V, V _{DS} = 30 V, T _J = 175 °C	-	-	150	
On-State Drain Current ^a	I _{D(on)}	V _{GS} = 4.5 V, V _{DS} ≥ 5 V	5	-	-	A
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 3.8 A	-	0.050	0.065	Ω
		V _{GS} = 4.5 V, I _D = 3.8 A, T _J = 125 °C	-	-	0.097	
		V _{GS} = 4.5 V, I _D = 3.8 A, T _J = 175 °C	-	-	0.115	
		V _{GS} = 2.5 V, I _D = 3.1 A	-	0.070	0.095	
Forward Transconductance ^b	g _{fs}	V _{DS} = 15 V, I _D = 2 A	-	8	-	S
Dynamic^b						
Input Capacitance	C _{ISS}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	-	488	610	pF
Output Capacitance	C _{OSS}		-	60	75	
Reverse Transfer Capacitance	C _{RSS}		-	36	45	
Total Gate Charge ^c	Q _g	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 3.8 A	-	4.4	6.6	nC
Gate-Source Charge ^c	Q _{gs}		-	1	-	
Gate-Drain Charge ^c	Q _{gd}		-	1	-	
Gate Resistance	R _g	f = 1 MHz	3	6.35	9.7	Ω
Turn-On Delay Time ^c	t _{d(on)}	V _{DD} = 15 V, R _L = 3.9 Ω I _D ≅ 3.8 A, V _{GEN} = 4.5 V, R _g = 1 Ω	-	8	12	ns
Rise Time ^c	t _r		-	13	20	
Turn-Off Delay Time ^c	t _{d(off)}		-	14	21	
Fall Time ^c	t _f		-	8	12	
Source-Drain Diode Ratings and Characteristics^b						
Pulsed Current ^a	I _{SM}		-	-	11	A
Forward Voltage	V _{SD}	I _F = 2.5 A, V _{GS} = 0 V	-	0.8	1.2	V

Notes

- a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.